

A novel random approach to diagnostic test generation

Osimiry, Emmanuel Ovie; Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan 2nd IEEE NORCAS Conference : 1-2 November 2016, Copenhagen, Denmark 2016 / [4] p. : ill <https://doi.org/10.1109/NORCHIP.2016.7792915>

A tool for random test generation targeting high diagnostic resolution

Osimiry, Emmanuel Ovie; Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 79-82 : ill http://www.eester.ee/record=b2150914*est